

FDD6690S

30V N-Channel PowerTrench® SyncFET™

General Description

The FDD6690S is designed to replace a single MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low $R_{\rm DS(ON)}$ and low gate charge. The FDD6690S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDD6690S as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDD6690A in parallel with a Schottky diode.

Applications

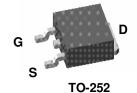
- DC/DC converter
- Motor Drives

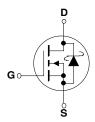
Features

• 40 A, 30 V $R_{DS(ON)} = 16 \ m\Omega \ @ \ V_{GS} = 10 \ V$ $R_{DS(ON)} = 24 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$

- Includes SyncFET Schottky body diode
- Low gate charge (17nC typical)
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- · High power and current handling capability

.





Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 3)	40	A
	- Pulsed	(Note 1a)	100	
P _D	Power Dissipation	(Note 1)	50	W
		(Note 1a)	2.8	
		(Note 1b)	1.3	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	2.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	45	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1b)	96	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDD6690S	FDD6690S	13"	16mm	2500 units

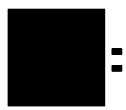
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	e 2)	II.	ı	l	
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 \text{ V}$, $I_D=14A$			245	mJ
I _{AR}	Drain-Source Avalanche Current				14	Α
Off Char	acteristics	-	-1	I		
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 1 \text{ mA}$	30			V
$\Delta BV_{DSS} \over \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$I_D = 10$ mA, Referenced to 25°C	"	19		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \qquad V_{GS} = 0 \text{ V}$			500	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)		•			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	1	2	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I _D = 10 mA, Referenced to 25°C		-3.3		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$\begin{split} &V_{GS} = 10 \ V, &I_{D} = 10 \ A \\ &V_{GS} = 4.5 \ V, &I_{D} = 8 \ A \\ &V_{GS} = 10 \ V, I_{D} = 10 \ A, T_{J} = 125 ^{\circ} C \end{split}$		10 15.5 16	16 24 26	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	60			Α
g FS	Forward Transconductance	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 10 \text{ A}$		27		S
Dynamic	Characteristics	•	•	•		•
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		2010		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		526		pF
C _{rss}	Reverse Transfer Capacitance			186		pF
Switchin	g Characteristics (Note 2)	1	1	<u>I</u>	I	
t _{d(on)}	Turn-On Delay Time	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A},$		10	18	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	18	ns
t _{d(off)}	Turn-Off Delay Time	_		34	55	ns
t _f	Turn-Off Fall Time	-		14	23	ns
Qq	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 10 \text{ A},$		17	24	nC
Q _{qs}	Gate-Source Charge	$V_{GS} = 10 \text{ V}$		6.2		nC
Q_{gd}	Gate-Drain Charge			5.5		nC
	ource Diode Characteristics		1	I.	I	<u> </u>
V _{SD}	Drain-Source Diode Forward Voltage	$\begin{array}{cccccccccccccccccccccccccccccccccccc$		0.49 0.56	0.7	V
t _{rr}	Diode Reverse Recovery Time	$I_{\rm F} = 3.5 \text{A},$		20		nS
Q _{rr}	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$ (Note 3)		19.7		nC

Electrical Characteristics

 $T_A = 25$ °C unless otherwise noted

Notes:

1. $R_{\theta,JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,CA}$ is determined by the user's board design.



a) $R_{\theta,JA} = 45$ °C/W when mounted on a 1in^2 pad of 2 oz copper



b) $R_{\theta JA} = 96^{\circ}C/W$ when mounted on a minimum pad.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%

3. Maximum current is calculated as: $\sqrt{\frac{P_D}{R_{DS(ON)}}}$

where P_D is maximum power dissipation at T_C = 25°C and $R_{DS(on)}$ is at $T_{J(max)}$ and V_{GS} = 10V. Package current limitation is 21A

Typical Characteristics

1.9

1.6

1.3

R_{DS(ON)}, NORMALIZED DRAIN-SOURCE ON-RESISTANCE I_D = 10A

V_{GS} = 10V

-25

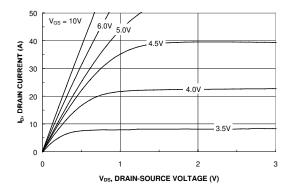


Figure 1. On-Region Characteristics.

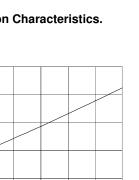


Figure 3. On-Resistance Variation with Temperature.

50

T_J, JUNCTION TEMPERATURE (°C)

75

100

25

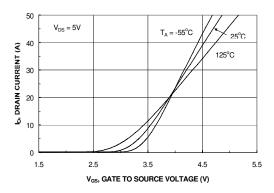


Figure 5. Transfer Characteristics.

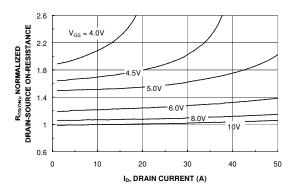


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

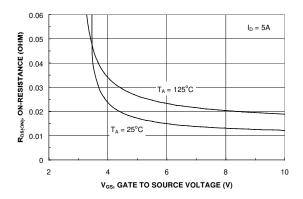


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

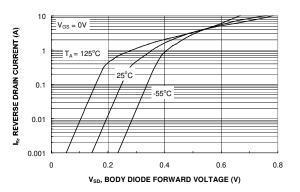
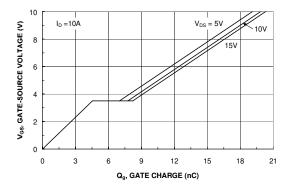


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



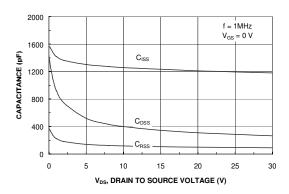
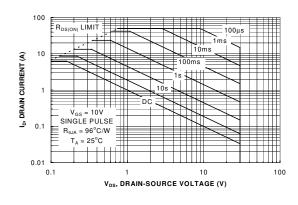


Figure 7. Gate Charge Characteristics.





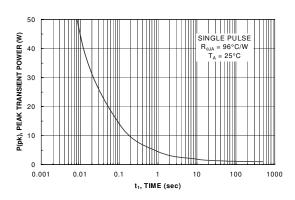


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

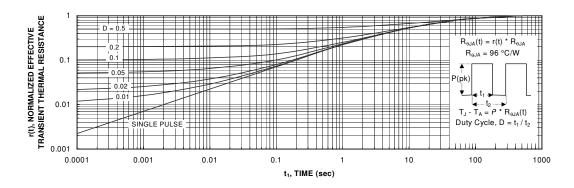


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDD6690S.

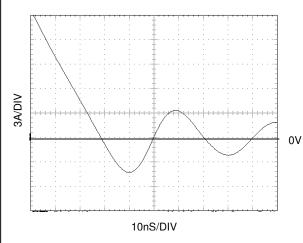


Figure 12. FDD6690S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDD6690A).

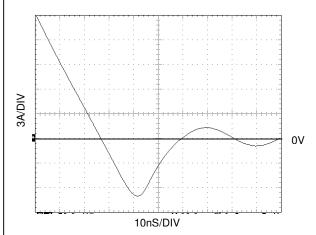


Figure 13. Non-SyncFET (FDD6690A) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

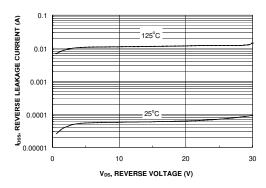


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

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